

next communication to the Applicant.

Application Number
Filing Date
First Named Inventor Rutten
Group Art Unit
Examiner Name
Attorney Docket US 018179



U.S. PATENT DOCUMENTS							
Examiner's Initials	Cite No.	Patent Number	Date	Name	Class	Sub- Class	Filing Date, If Approp.
	AA	6,075,373	13 June 2000	Iino			
ES	AB	6,169,410 B1	2 January 2001	Grace et al.			
EP	AC	(copending application)? "CHIP-MOUNTED CONTACT SPRINGS"	10,805,689	Rutten			(concurrent)
	AD						
	AE		-				
	AF						
	AG						
	AH						

FOREIGN PATENT DOCUMENTS								
Examiner's Initials	Cite I	Patent Number	Date	Country	Class	Sub- Class	Translation	
							Yes	No
Σp	AI	EP 0 755 071 A2	18 July 1996	Europe				
	AJ					1		
	AK							
	AL							
	AM							ļ

Examiner's Initials	Cite No.	Other (Include Author, Title, Date, Pertinent Pages, Etc.)
Û	AN	"Introducing WOW Technology", http://www.formfactor.com/about/wow/wow_pg2.html
W	AO	"Introducing WOW Technology", http://www.formfactor.com/about/wow/wow_pg5.html
EP	AP	"Focus on FormFactor", THE FINAL TEST REPORT, Vol. 12, No. 09, September 2001, Ikonix Corp. P.O. Box 1938, Lafayette, CA 94549-1938
ÉP	AQ	"Flip-Chip Bonding on 6-um Pitch using Thin-Film Microspring Technology", Donald L. Smith et at., Xerox Palo Alto Research Center, Proceedings, 48 th Electronic Components and Technology Conference, IEEE, May 1998.
	AR	

	AR			
Examiner		Evan	Pert	Date Considered 6/5/03
Examiner:	Initial i	f reference con	sidered, whether	r or not citation is in conformance with MPEP 609;

Draw line through citation if not in conformance and not considered. Include a copy of this form with